

10/564447

DOCKET NO.: 284475US3PCT

IAP20 Rec'd 12 JAN 2006

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

IN RE APPLICATION OF: Dai KOBAYASHI, et al.

SERIAL NO.: NEW U.S. PCT APPLICATION

FILED: HEREWITH

INTERNATIONAL APPLICATION NO.: PCT/JP04/09911

INTERNATIONAL FILING DATE: July 12, 2004

FOR: PROBE FOR SCANNING PROBE MICROSCOPE AND METHOD OF PRODUCING THE SAME

**REQUEST FOR PRIORITY UNDER 35 U.S.C. 119  
AND THE INTERNATIONAL CONVENTION**

Commissioner for Patents  
Alexandria, Virginia 22313

Sir:

In the matter of the above-identified application for patent, notice is hereby given that the applicant claims as priority:

**COUNTRY**  
Japan

**APPLICATION NO**  
2003-275200

**DAY/MONTH/YEAR**  
16 July 2003

Certified copies of the corresponding Convention application(s) were submitted to the International Bureau in PCT Application No. PCT/JP04/09911. Receipt of the certified copy(s) by the International Bureau in a timely manner under PCT Rule 17.1(a) has been acknowledged as evidenced by the attached PCT/IB/304.

Respectfully submitted,  
OBLON, SPIVAK, McCLELLAND,  
MAIER & NEUSTADT, P.C.



C. Irvin McClelland  
Attorney of Record  
Registration No. 21,124  
Surinder Sachar  
Registration No. 34,423

Customer Number

**22850**

(703) 413-3000  
Fax No. (703) 413-2220  
(OSMMN 08/03)